

Investigation of (non) polar Crystallographic Structures of (un) doped HfO₂ Bulk Ceramics and Nanoparticles

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Ferroelectric properties were discovered in HfO₂ thin films, which enabled HfO₂ to be considered for lead free ferroelectric capacitors or transistors for non-volatile memories. At ambient conditions HfO₂ is monoclinic and nonpolar, but the ferroelectricity discovered in thin films has been attributed to the formation of an orthorhombic polar phase due to chemical doping and stresses induced by the substrate and capping layer.[1-2] Although the ferroelectric properties of doped HfO₂ films have been rigorously investigated, fundamentals of the relationship between the observed ferroelectric properties and underlying structure are still not fully understood.

To elucidate fundamentals associated with the phase stability and crystallography of these systems, we present here results on powder and bulk compositions of HfO₂-based materials. Specifically, we investigated Y-, Gd-, and Sc-doped HfO₂ nanoparticles and bulk ceramics at various dopant concentrations and as a function of synthesis conditions. These dopants can induce the formation of the cubic or tetragonal phases in the bulk and nanoparticle forms of HfO₂, [3-5] a pathway toward the formation of the orthorhombic phase at lower temperatures. X-ray diffraction patterns were measured for each of the doped HfO₂ powders to determine the structures changes that occurred due to doping and heat treatment. It is observed in the Y and Gd-doped HfO₂ XRD patterns, that the cubic phase can be formed and sustained at ambient conditions. Further analysis of the diffraction patterns was performed using Rietveld Refinement. These results were used to determine the change in phase fractions and lattice parameters of the HfO₂ crystal structure. Based on these results, we consider Y and Gd-doping to be pathways to realizing ferroelectric properties in HfO₂ bulk ceramics.

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